

IGBT

TRENCHSTOPTM IGBT4 Medium Power Chip IGC99T120T8RM

Data Sheet

Industrial Power Control

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TRENCHSTOPTM IGBT4 Medium Power Chip

Features:

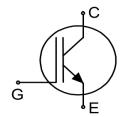
- 1200V trench & field stop technology
- Low switching losses
- Soft turn off
- Positive temperature coefficient
- Easy paralleling

Recommended for:

Medium power modules

Applications:

• Medium power drives



Chip Type	V _{CE}	<i>I</i> _{Cn} ¹	Die Size	Package
IGC99T120T8RM	1200V	100A	9.5mm x 10.39mm	Sawn on foil

Mechanical Parameters

Die size		9.5 x 10.39			
Emitter pad size		See chip drawing	2		
Gate pad size		1.31 x 0.811	mm ²		
Area total		98.71			
Thickness		120	μm		
Wafer size		200	mm		
Maximum possible ch	ips per wafer	258			
Passivation frontside		Photoimide			
Pad metal 3200nm AlSiCu					
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process			
Die bond Electrically conductive epoxy glue and soft s			lder		
Wire bond		Al, ≤500μm			
Reject ink dot size		Ø 0.65mm; max. 1.2mm	Ø 0.65mm; max. 1.2mm		
Storago environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°0 <6 months			
Storage environment	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or inchange humidity <25%RH, temperature 17°C – 25°C, <6 mg			

L7683O, L7683U 3 Rev. 2.1, 20.08.2015

¹ Nominal collector current at T_C =100°C for chip packaged in power modules, see application example cited on page 5.



Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _{vj} =25°C	V _{CE}	1200	V
DC collector current, limited by $T_{\rm vj\;max}^{\;\;2}$	I _C	-	Α
Pulsed collector current, t_p limited by $T_{vj \max}$ 3	I _{C,puls}	300	Α
Gate-emitter voltage	V_{GE}	±20	V
Operating junction temperature	T_{vj}	-40 +175	°C
Short circuit data $^{3/4}$ V_{GE} =15V, V_{CC} =800V, T_{vj} =150°C	t _{sc}	10	μs

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Symbol Conditions		Value			Unit
rai ailletei	Symbol	Conditions	min.	typ.	max.	•
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V, I_{C} =3.8mA	1200	-	-	
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =100A	1.53	1.75	1.97	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =3.8mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.1	5.8	6.4	
Zero gate voltage collector current	I _{CES}	$V_{\text{CE}} = 1200 \text{V}, \ V_{\text{GE}} = 0 \text{V}$	-	-	1.3	μA
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$	ı	ı	120	nA
Integrated gate resistor	r _G			7.5		Ω

Electrical Characteristics ³

Parameter	Symbol Conditions		Value			Unit
raiametei	Symbol	Conditions	min.	typ.	max.	Onit
Collector-emitter saturation voltage	V_{CEsat}	V_{GE} =15V, I_{C} =100A, T_{vj} =150°C	-	2.05	-	٧
Input capacitance	C _{ies}	V _{CE} =25V,	-	6300	1	ςE
Reverse transfer capacitance	C _{res}	V_{GE} =0V, f =1MHz T_{vj} =25°C	-	270	-	pF

² Depending on thermal properties of assembly.

³ Not subject to production test - verified by design/characterization.

⁴ Allowed number of short circuits: <1000; time between short circuits: >1s.



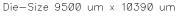
Further Electrical Characteristics

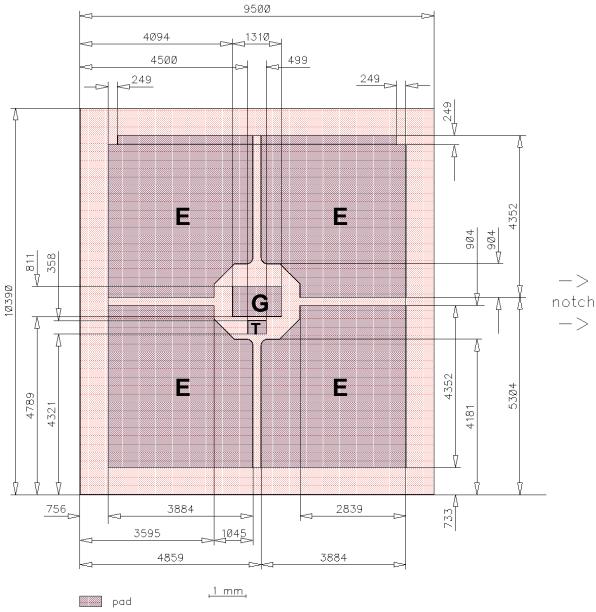
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	IFS100B12N3E4_B31	Rev. 2.0
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Chip Drawing





E = Emitter

G = Gate

T = Test pad do not contact



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	18.02.2015
2.1	Update disclaimer	20.08.2015

Relevant App	lication Notes



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